

**Search Notes**

Application/Control No.

10/706,238

Examiner

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Applicant(s)/Patent under  
Reexamination

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Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	1	2/16/2006	JSL
716	2-5	2/16/2006	JSL
712	19	2/16/2006	JSL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
716	1	2/16/2006	JSL
716	2	2/16/2006	JSL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	2/16/2006	JSL